

Notice of References Cited	Application/Control No. 10/661,535	Applicant(s)/Patent Under Reexamination HIRAKAWA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0191008	12-2002	Naka et al.	345/690
*	B	US-2001/0054993	12-2001	Kanazawa et al.	345/60
*	C	US-2003/0011540	01-2003	Tokunaga et al.	345/60
*	D	US-2003/0067425	04-2003	Tokunaga et al.	345/60
*	E	US-2003/0098826	05-2003	Moon, Seong Hak	345/75.2
*	F	US-2001/0017605	08-2001	Hashimoto et al.	345/60
*	G	US-2003/0011542	01-2003	Nakamura, Hideto	345/63
*	H	US-2003/0189534	10-2003	Myoung et al.	345/67
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000148085 A	05-2000	Japan	AWAJI, NORIYUKI	G09G 03/28
	O	JP 2000276106 A	10-2000	Japan	TOKUNAGA et al.	G09G 03/28
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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